



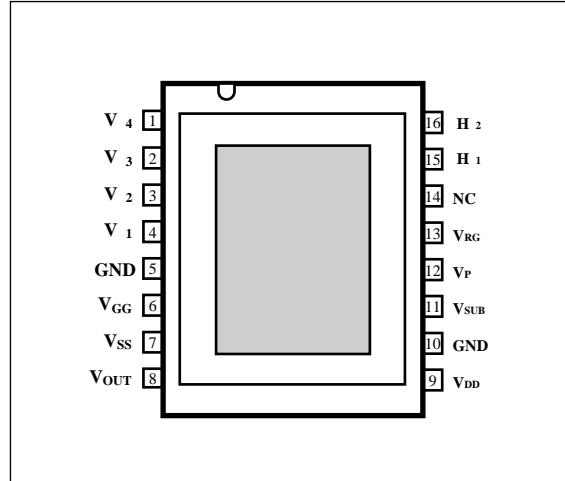
## Description

The Ai329 is a 290K pixels CCD area sensor for CCIR 1/3inch video cameras. Buried photodiode and micro lens are adopted for low noise, low smear and high sensitivity. This chip also features a strong anti-blooming and electronic shutter with variable charge-storage time.

## Feature

- Micro Lens for high sensitivity
- Image-lag is negligible and excellent blooming suppression is performed.
- TTL level(5V) operation on HCCD & RG electrodes.
- 16 pin plastic-DIP.
- Variable electronic shutter of 1/50 to 1/100,000 sec.
- High sensitivity and low smear.

## Pin Configuration

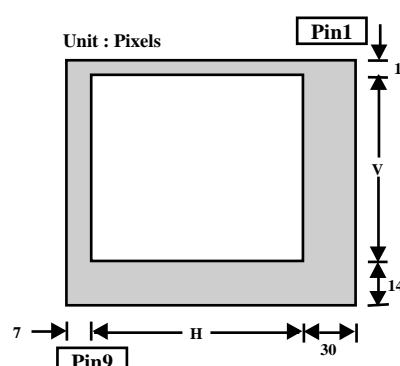


**16 Pin Plastic - DIP  
( Top View )**

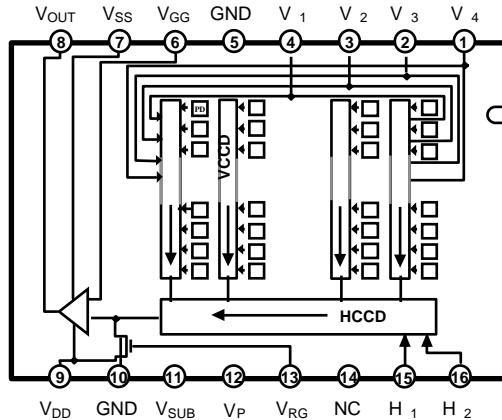
## Structure

- Architecture : IT - CCD
- Optical size : 1/3 inch format
- Chip size : 6.0(H) x 5.2(V) mm<sup>2</sup>
- Number of effective pixels :
  - 500 (H) x 582 (V) about 290K pixels
- Number of total pixels :
  - 537 (H) x 597 (V) about 320K pixels
- Pixel size : 9.8 (H) x 6.3 (V)  $\mu\text{m}^2$
- Optical black area
  - Horizontal direction : Front 7 pixels Rear 30 pixels
  - Vertical direction : Front 14 pixels Rear 1 pixels
- Number of dummy bits
  - Horizontal : 16
  - Vertical : 1 ( Even field only )

## Optical black position( Top View )



## Block Diagram



## Pin Description

No.	Symbol	Description	No.	Symbol	Description
1	V <sub>4</sub>	Vertical register transfer clock 4	9	V <sub>DD</sub>	Output amplifier drain bias
2	V <sub>3</sub>	Vertical register transfer clock 3	10	GND	Ground
3	V <sub>2</sub>	Vertical register transfer clock 2	11	V <sub>SUB</sub>	Substrate(Overflow drain)bias
4	V <sub>1</sub>	Vertical register transfer clock 1	12	V <sub>P</sub>	Protection bias
5	GND	Ground	13	V <sub>RG</sub>	Reset gate clock
6	V <sub>GG</sub>	Output amplifier gate bias	14	NC	No connection
7	V <sub>SS</sub>	Output amplifier source bias	15	H <sub>1</sub>	Horizontal register transfer clock 1
8	V <sub>OUT</sub>	CCD Output signal	16	H <sub>2</sub>	Horizontal register transfer clock 2

## Absolute Maximum Ratings

Parameter	Symbol	Value	Unit
Substrate voltage	V <sub>SUB</sub> - GND	-0.3 to +55	V
Supply voltage	V <sub>DD</sub> , V <sub>OUT</sub> , V <sub>SS</sub> - GND V <sub>DD</sub> , V <sub>OUT</sub> , V <sub>SS</sub> - V <sub>SUB</sub>	-0.3 to +18 -55 to +10	V V
Vertical clock input voltage	V <sub>1, 2, 3, 4</sub> - GND V <sub>1, 2, 3, 4</sub> - V <sub>P</sub> V <sub>1, 2, 3, 4</sub> - V <sub>SUB</sub>	-10 to +20 -0.3 to +27 -55 to +10	V V V
Horizontal clock input voltage	H <sub>1</sub> , H <sub>2</sub> - GND	-10 to +15	V
Between vertical clock input pins	V <sub>x</sub> - V <sub>y</sub>	-10 to +15	V
Between horizontal clock and vertical clock input pins	H <sub>1</sub> , H <sub>2</sub> - V <sub>4</sub>	-17 to +17	V
Output pin voltage	RG, V <sub>GG</sub> - GND RG, V <sub>GG</sub> - V <sub>SUB</sub>	-10 to +15 -55 to +10	V V
Protective circuit voltage	V <sub>P</sub> - V <sub>SUB</sub>	-65 to 0.3	V
Storage temperature	T <sub>STG</sub>	-30 to 80	
Operation temperature	T <sub>OPR</sub>	-10 to 60	

## Bias Condition

Parameter	Symbol	Min.	Typ.	Max.	Unit	Remark
Output amplifier drain voltage	$V_{dd}$	14.5	15.0	15.5	V	
Output amplifier gate voltage	$V_{gg}$	1.5	2.0	2.5	V	
Output amplifier source voltage	$V_{ss}$			Ground through 680 Resistor, ±5%		
Substrate voltage adjustment range	$V_{sub}$	5		15	V	
Fluctuation range after substrate voltage adjustment	$V_{sub}$	-1		1	V	
Reset gate clock voltage adjustment range	$V_{rgl}$	0		4	V	
Fluctuation range after reset gate voltage adjustment	$V_{rgl}$	-3		3	%	
Protection bias	$V_p$			Set to low level of vertical transfer clock		

## DC Characteristics

Parameter	Symbol	Min.	Typ.	Max.	Unit
Output amplifier drain current	$I_{DD}$	-	3	-	mA

## Driving Condition

Parameter	Symbol	Min.	Typ.	Max.	Unit
Vertical clock high voltage	$V_{H1}, V_{H3}$	14.5	15.0	15.5	V
Vertical clock middle voltage	$V_{M1, 2, 3, 4}$	-0.2	0.0	0.2	V
Vertical clock low voltage	$V_{L1, 2, 3, 4}$	-9.0	-8.5	-8.0	V
Horizontal clock high voltage	$H_{H1, 2}$	4.5	5.0	5.5	V
Horizontal clock low voltage	$H_{L1, 2}$	-0.5	0.0	0.5	V
RG clock voltage difference	$RG_{HL}$	4.7	5.0	5.3	V
Substrate clock voltage	$V_{SUB}$	23	24	25	V

**Electro-optical Performance**

Item	Symbol	Min.	Typ.	Max.	Unit	Measurement Method	Remark
Sensitivity	SENS	55	70		mV/Lux	1	
Saturation signal	V <sub>SAT</sub>	800			mV	2	Temp=60
Smear	S <sub>MR</sub>			0.015	%	3	
Blooming	BL			1	%	4	
Video signal shading	OSNU			15	%	5	
Dark signal level	V <sub>DARK</sub>			2	mV	6	Temp=60
Dark signal shading	DSNU			2	mV	7	Temp=60

**Measurement Method****1. Sensitivity**

Set to SILC ( Standard Illumination Conditions\* )

Measure the average value of signal output ( Vout )

Calculate the efficiency of Vout to light intensity

**2. Vsat**

Adjust light intensity to 200 times of SILC

Measure the average value of signal output

**3. Smear**

Adjust light intensity to 200 times of SILC & readout clock

Measure the signal output at horizontal optical black ( Vhopb )

Measure the signal output at vertical blanking dummy ( Vvbd )

Smear = { ( Vvbd - Vhopb ) / Vsat } × 100 ( % )

**4. Blooming**

Adjust light intensity to 200 times of SILC & readout clock

Measure the signal output at horizontal optical black ( Vhopb )

Measure the signal output at blooming dummy area ( Vbd )

Blooming = { ( Vbd - Vhopb ) / Vsat } × 100 ( % )

**5. OSNU**

Set to SILC

Measure the average value of signal output ( Vout )

Measure the maximum value and the minimum value of signal output

OSNU = ( Vmax - Vmin ) / Vout 100 (%)

**6. Vdark**

Measure the average value of signal output at dark condition

**7. DSNU**

Measure the voltage difference between minimum and maximum of dark signal

**\* Standard Illumination Conditions**

Measure the average value of output of linear region

At this time, measure the light intensity of illumination at CCD face plate

Define SILC with above

Light source: Tungsten lamp(3100K)

Use a standard test lens at F8

## **Notes on Handling**

### **1) Static charge prevention**

CCD image sensors are easily damaged by static discharge. Before handling be sure to take the following protective measures.

- a) Either handle bare handed or use non-chargeable gloves, clothes or material. Also use conductive shoes.
- b) When handling directly use an earth band.
- c) Install a conductive mat on the floor or working table to prevent the generation of static electricity.
- d) Ionized air is recommended for discharge when handling CCD image sensor.
- e) For the shipment of mounted substrates, use boxes treated for the prevention of static charges.

### **2) Soldering**

- a) Make sure the package temperature does not exceed 80°C.
- b) Solder dipping in a mounting furnace causes damage to the glass and other defects. Use a ground 30W soldering iron and solder each pin in less than 2 seconds. For repairs and remount, cool sufficiently.
- c) To dismount an image sensor, do not use a solder suction equipment. When using an electric desoldering tool, use a thermal controller of the zero cross On/Off type and connect it to ground.

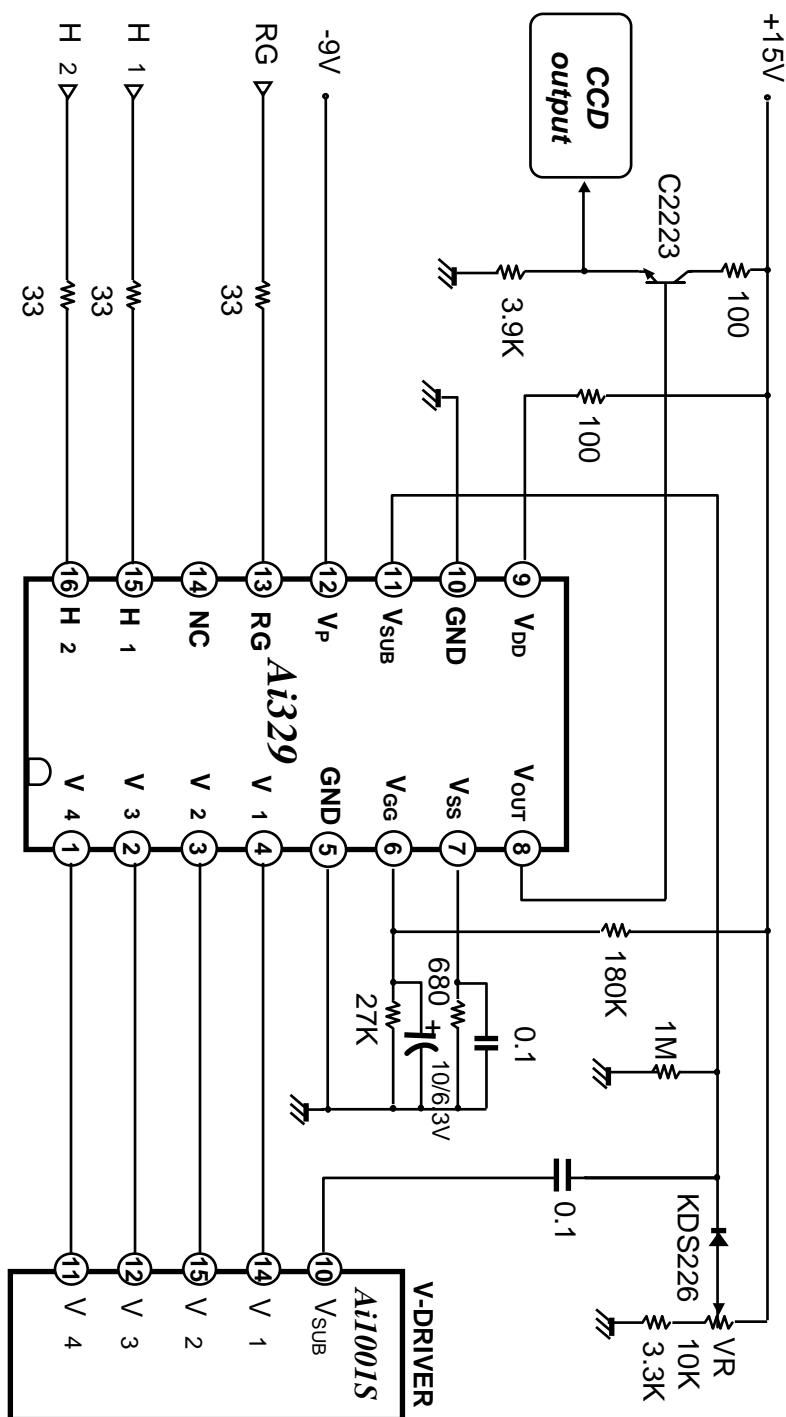
### **3) Dust and Dirt protection**

- a) Perform all assembly operations in a clean room (class 1000 or less).
- b) Do not either touch glass plates by hand or have any object come in contact with glass surfaces. Should dirt stick to a glass surface, blow it off with an air blower. (For dirt stuck through static electricity ionized air is recommended.)
- c) Clean with a cotton bud and ethyl alcohol if the grease stained. Be careful not to scratch the glass.
- d) Keep in a case to protect from dust and dirt. To prevent dew condensation, preheat or precool when moving to a room with great temperature differences.

### **4) Others**

- a) Do not expose to strong light (sun rays) for long periods.
- b) Exposure to high temperature or humidity will affect the characteristics. Accordingly avoid storage or usage in such conditions.

## Application Circuit



### Package Dimension (16 Pin Plastic-DIP)

